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PATENT APPLICATION

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the Application of

Shuichi MIURA

Group Art Unit: 1751

Application No.: 10/717,504

Examiner: J. THOMAS

Filed: November 21, 2003

Docket No.: 117803

For: CONDUCTIVE COMPOSITION AND CERAMIC ELECTRONIC COMPONENT

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

Further to the Information Disclosure Statement (IDS) filed on February 23, 2006, attached is an English language translation of the communication from the Japanese Patent Office (reference 1 of this IDS) citing reference JP A 04-043504 (reference 1 of the February 23 IDS). It is expressly requested that the information be expressly considered during the prosecution of this application, and that the reference be made of record therein and appear among the "References Cited" on any patent to issue therefrom.

Respectfully submitted,

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<p>DEPOSIT ACCOUNT USE AUTHORIZATION Please grant any extension necessary for entry; Charge any fee due to our Deposit Account No. 15-0461</p>

Sheet 1 of 1

Form PTO-1449 (REV. 1/06)		US Dept. of Commerce PATENT & TRADEMARK OFFICE		ATTY DOCKET NO. 117803		APPLICATION NO. 10/717,504	
INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary)				APPLICANT(S) Shuichi MIURA			
				FILING DATE November 21, 2003		GROUP 1751	
U.S. PATENT DOCUMENTS							
Examiner Initials	Cite No.	Document Number	Date	Name			
FOREIGN PATENT DOCUMENTS							
Examiner Initials	Cite No.	Document Number	Date	Country	With English Abstract	With English Translation	
	1	Japanese Patent Office paper citing reference JP A 04-043504	08/02/2005	Japan		X	
OTHER DOCUMENTS							
Examiner Initials	Cite No.	(Including Author, Title, Date, Pertinent Pages, etc.)					
EXAMINER					DATE CONSIDERED		
Examiner: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

Date: April 20, 2006